

ON Semiconductor®

FQB27N25TM-F085/FQI27N25TU-F085

N-Channel MOSFET 250 V, 25.5 A, 131 mΩ

Features

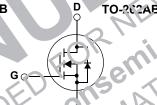
- \blacksquare Typ R_{DS(on)} = 108m Ω at V_{GS} = 10V, I_D = 25.5A
- Typ $Q_{q(tot)}$ = 45nC at V_{GS} = 10V, I_D = 27A
- UIS Capability
- RoHS Compliant
- Qualified to AEC Q101

Applications

- Automotive Engine Control
- Powertrain Management
- Solenoid and Motor Drivers
- Electronic Steering
- Integrated Starter/Alternator
- Distributed Power Architectures and VRM
- Primary Switch for 12V Systems



TO-262 \B



MOSFET Maximum Rating unless scherwise noted

Symbol	rameter	Ratings	Units
V_{DSS}	Drain to Sc ce Voltage	250	V
V_{GS}	Gate to Sc ce Volta :	±30	V
	r un currei Cont uous (V _{GS} =10) (Note 1) T _C =25°C	25.5	Α
ID	n Current 7 _C = 25°C	See Figure 4	_ A
Eng	Single Pr : Avalanche Energy (Note 2)	972	mJ
1p	'owe, Dissipation	417	W
P_{D}	L _rate abo 'e 2 ⁵ °C	3.3	W/°C
T_{J}, T_{G}	Operating and Stolage Temperature	-55 to + 150	οС
· JC	Thermal Resistance, Junction to Case	0.3	°C/W
$R_{\theta J \Lambda}$	Maximum 1 hermal Resistance, Junction to Ambient (Note 3)	43	°C/W

Package Marking and Ordering Information

Device Marking Device		Package	Reel Size	Tape Width	Quantity
FQB27N25TM	FQB27N25TM-F085	TO-263AB	330mm	24mm	800 units
FQI27N25TU	FQI27N25TU-F085	TO-262AB	Tube	N/A	50 units

- 1: Current is limited by bondwire configuration.
- Starting T_J = 25°C, L = 4.67mH, I_{AS} = 20.4A, V_{DD} = 100V during inductor charging and V_{DD} = 0V during time in avalanche.
 R_{θJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{θJC} is guaranteed by design while R_{θJA} is determined by the user's board design. The maximum rating presented here is based on mounting on a 1 in² pad of 2oz copper.

Units

Max.

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted.

Parameter

Off Characteristics							
B _{VDSS}	Drain to Source Breakdown Voltage	I _D = 250μA, \	/ _{GS} = 0V	250	-	-	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} =250V,	$T_{\rm J} = 25^{\rm o}{\rm C}$	-	-	1	μΑ
		$V_{GS} = 0V$	$T_J = 150^{\circ} C(Note 4)$	-	-	250	uA
less	Gate to Source Leakage Current	$V_{CS} = \pm 30V$		-	-	±100	nA

Test Conditions

Min.

Тур.

On Characteristics

Symbol

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D}$	= 250μA	3.0	4 1		V
R _{DS(on)}	Drain to Source On Resistance	I _D = 25.5A,	$T_{J} = 25^{\circ}C$	-	10	13	mΩ
		V _{GS} = 10V	$T_J = 150^{\circ}C(Note 4)$		265	311	mΩ

Dynamic Characteristics

C _{iss}	Input Capacitance	1800 -	pF
C _{oss}	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$ $f = 1MHz$	pF
C _{rss}	Reverse Transfer Capacitance	- 45 -	pF
R_g	Gate Resistance	f = 1MH 0.82 -	Q
$Q_{g(ToT)}$	Total Gate Charge at 10V	V_C to 10 = 125 \vec{v} - 45 49	110
$Q_{g(th)}$	Threshold Gate Charge	$V_{GS} = 2V$ $I_D = 27A$ - $\sqrt{33}$ 4	nC
Q_{gs}	Gate to Source Gate Charge	12	nC
Q_{gd}	Gate to Drain "Miller" Charge	33 -	nC

Switching Character stics

t _{on} Turn-On ne	-	-	196	ns
t _{d(on)} T n L ¬y	-	36	-	ns
$v_{DD} = 125V_{DD} = 27A$	-	122	-	ns
$t_{d(off)}$ Isin -Off Is	-	81	-	ns
Fa T	-	60	-	ns
t _{off} irn-Off Tirne	-	-	164	ns

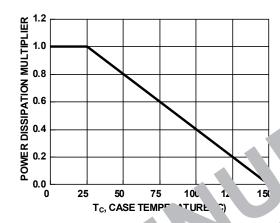
Prair Source Diode Characteristics

1						
V	Source to Lirain Diode Vultage	$I_{SD} = 25.5A, V_{GS} = 0V$	1	-	1.5	V
VSC	Source to Drain block Voltage	I_{SD} = 12.75A, V_{GS} = 0V	1	-	1.25	V
i _i .	ReverseRecovery rime	$I_F = 27A$, $dI_{SD}/dt = 100A/\mu s$,	1	205	238	ns
Q _{rr}	Reverse -Recovery Charge	V _{DD} =200V	-	1.8	2.3	nC

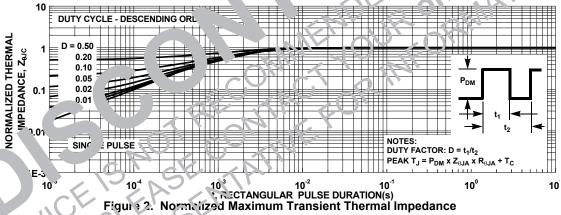
Notes:

4: The maximum value is specified by design at T_J = 150°C. Product is not tested to this condition in production.

Typical Characteristics



tion vs. Case Figure 1. Normalize ower SSI, en eratur



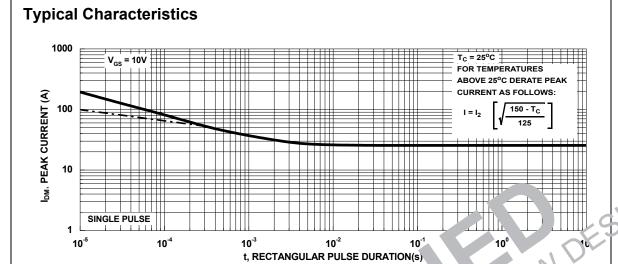


Figure 3. Peak Current Capabil.

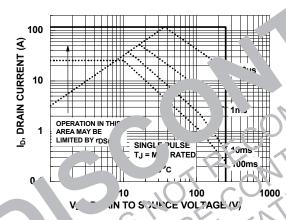
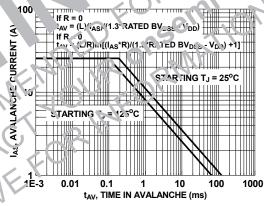
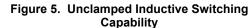


Fig. re Forward Blas Safe Operating Arda



NOTE: Refer to ON Semiconductor Application Notes AN7514 and AN7515



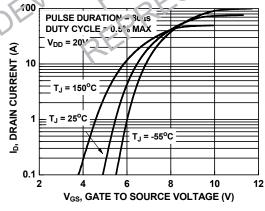


Figure 6. Transfer Characteristics

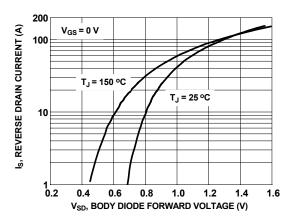


Figure 7. Forward Diode Characteristics

Typical Characteristics

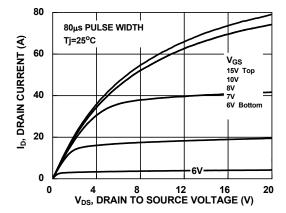


Figure 8. Saturation Characteristics

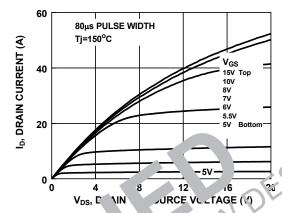
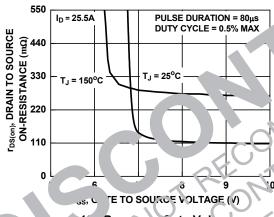


Figure Satu tion aracteristics



qui R_{DSON} vo. Gate Voltage

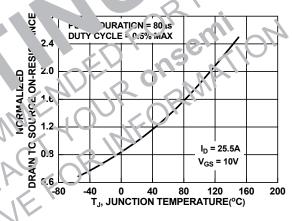


Figure 11. Normalized R_{DSON} vs. Junction Temperature

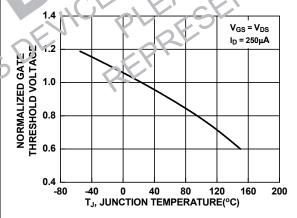


Figure 12. Normalized Gate Threshold Voltage vs. Temperature

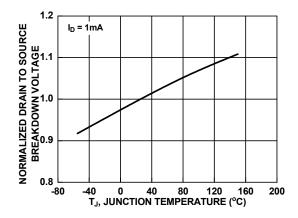


Figure 13. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

Typical Characteristics

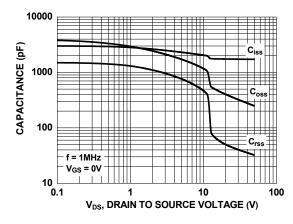


Figure 14. Capacitance vs. Drain to Source Voltage

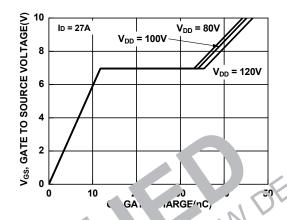


Figure 15. `ate C. rge s. Gate to Source V tage



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